

# GT10N65 Series

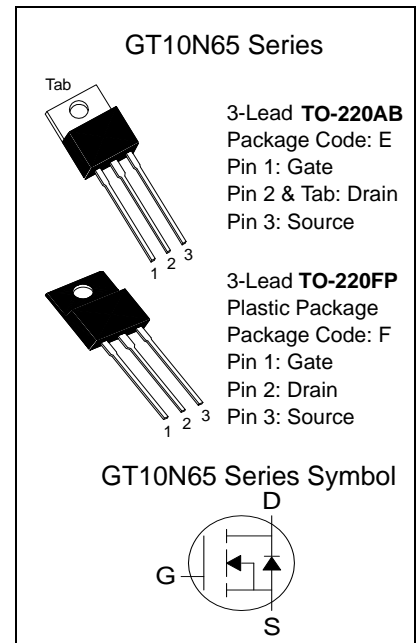
N-Channel Power MOSFET (650V,10A)

## Applications

- Switch Mode Power Supply
- Uninterruptable Power Supply
- High Speed Power Switching

## Features

- GT10N65 is a High voltage NChannel enhancement mode power MOSFET chip fabricated in advanced silicon epitaxial planar technology
- Advanced termination scheme to provide enhanced voltageblocking capability
- Avalanche Energy Specified
- Source to Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode;
- The packaged product is widely used in AC-DC power suppliers, DCDC converters and Hbridge PWM motor drivers



## Absolute Maximum Ratings

Symbol	Parameter	Value		Units
$V_{DSS}$	Drain-Source Voltage	650		V
$I_D$	Continuous Drain Current ( $V_{GS}@10V, T_C=25^\circ C$ )	10		A
	Continuous Drain Current ( $V_{GS}@10V, T_C=100^\circ C$ )	6.4		A
$I_{DM}$	Pulsed Drain Current <sup>*1</sup>	36		A
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$		V
$P_D$	Total Power Dissipation ( $T_C=25^\circ C$ )	TO-220AB	150	W
		TO-220FP	50	
	Linear Derating Factor	TO-220AB	1.25	W/ $^\circ C$
		TO-220FP	0.4	
$E_{AS}$	Single Pulse Avalanche Energy <sup>*2</sup>	700		mJ
$I_{AR}$	Avalanche Current <sup>*1</sup>	10		A
$E_{AR}$	Repetitive Avalanche Energy <sup>*1</sup>	66		mJ
$T_J$	Operating Junction Temperature Range	-55 to 150		$^\circ C$
$T_{stg}$	Storage Temperature Range	-55 to 150		$^\circ C$

\*1: Repetitive rating; pulse width limited by max. junction temperature

\*2: Starting  $T_J=25^\circ C, L=1.2mH, R_G=25\Omega, I_{AS}=10A$

\*3:  $I_{SD}\leq 14A, di/dt\leq 130A/us, V_{DD}\leq V_{(BR)DSS}, T_J\leq 150^\circ C$

## Thermal Characteristics

Symbol	Parameter	Value		Units
$R_{\theta JC}$	Thermal Resistance Junction to Case (Max.)	TO-220AB	1.3	$^\circ C/W$
		TO-220FP	5	
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (Max.)	62		$^\circ C/W$

## Electrical Characteristics (T<sub>j</sub>=25°C, unless otherwise specified)

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	650	-	-	V
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	Reference to 25°C, I <sub>D</sub> =1mA	-	0.58	-	V/°C
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V	-	-	10	uA
I <sub>GSSF</sub>	Gate-Source Forward Leakage	V <sub>gsf</sub> =30V, V <sub>DS</sub> =0V	-	-	100	nA
I <sub>GSSR</sub>	Gate-Source Reverse Leakage	V <sub>gsr</sub> =-30V, V <sub>DS</sub> =0V	-	-	-100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	2	-	4	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =5.0A <sup>*4</sup>	-	0.72	0.86	Ω
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =40V, I <sub>D</sub> =5.0A		5	-	S
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1MHz	-	1430	-	pF
C <sub>oss</sub>	Output Capacitance		-	117	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	2.2	-	
t <sub>d(on)</sub>	Turn-on Delay Time	(V <sub>DD</sub> =325V, I <sub>D</sub> =10A, R <sub>G</sub> =10Ω, R <sub>D</sub> =32Ω) <sup>*4</sup>	-	47	-	ns
t <sub>r</sub>	Rise Time		-	75	-	
t <sub>d(off)</sub>	Turn-off Delay Time		-	345	-	
t <sub>f</sub>	Fall Time		-	67	-	
Q <sub>g</sub>	Total Gate Charge	(V <sub>DS</sub> =525V, I <sub>D</sub> =10A, V <sub>GS</sub> =10V) <sup>*4</sup>	-	44		nC
Q <sub>gs</sub>	Gate-Source Charge		-	10		
Q <sub>gd</sub>	Gate-Drain Charge		-	16		

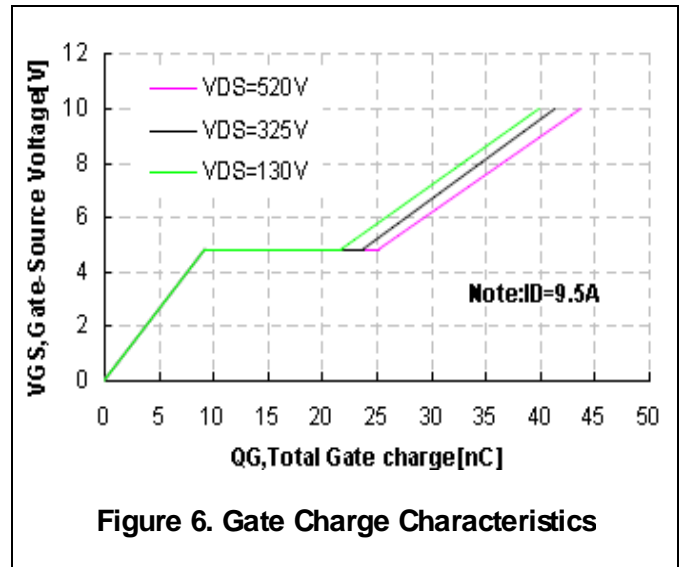
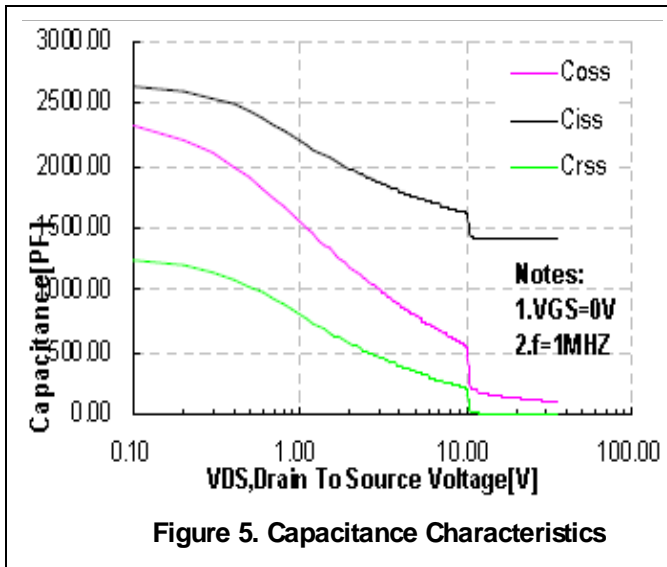
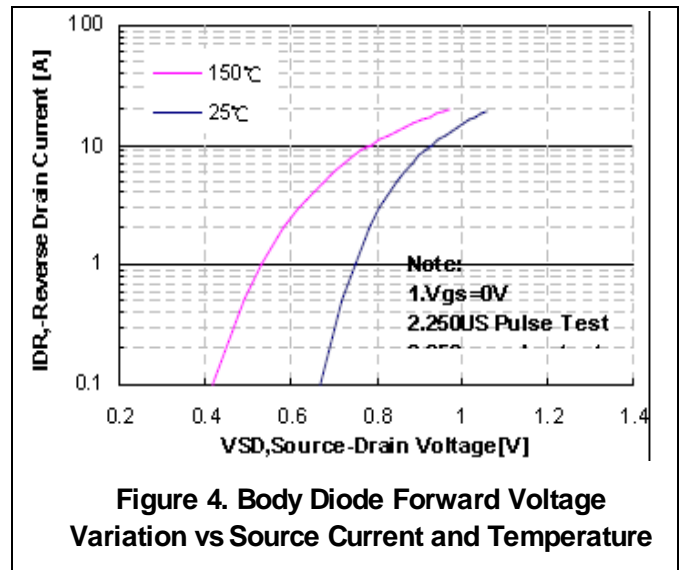
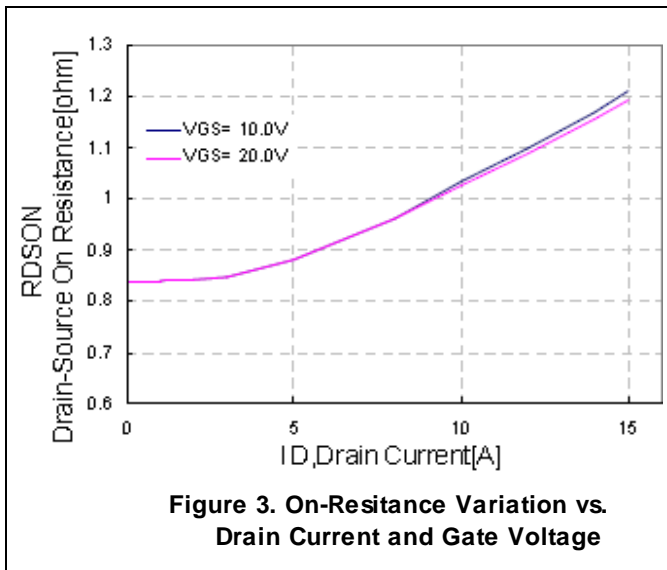
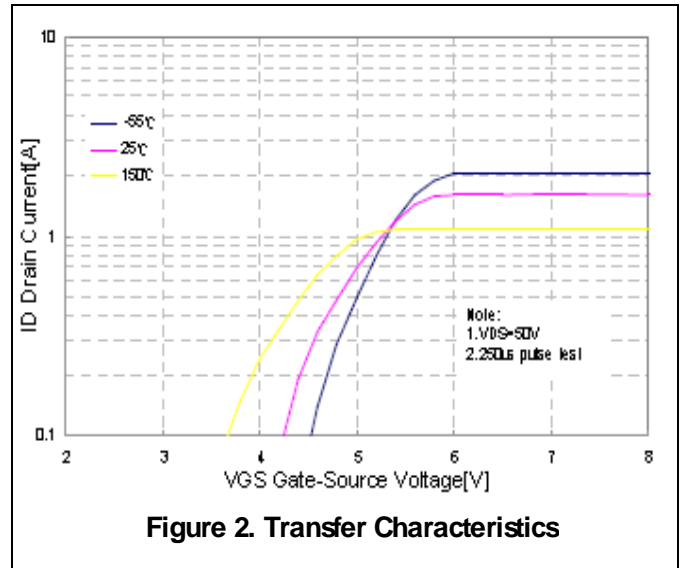
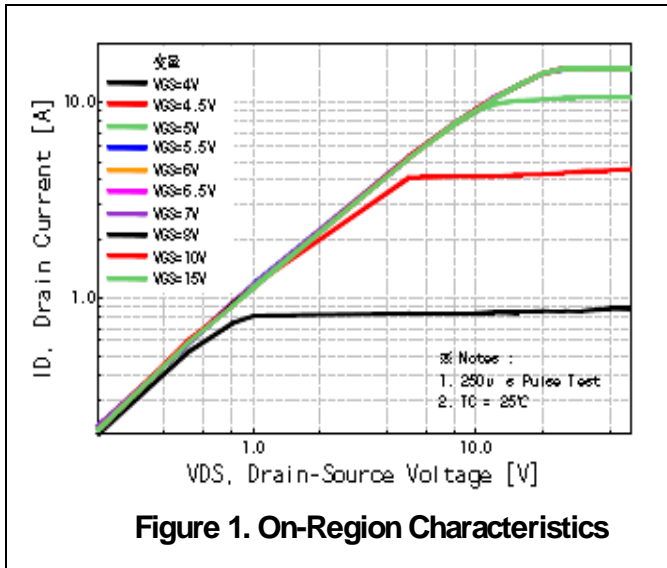
## Source-Drain Diode

Symbol	Characteristic		Min.	Typ.	Max.	Units
I <sub>S</sub>	Continuous Source Current (Body Diode)	Page1 MOSFET symbol showing the integral reverse P-N junction diode.	-	-	10	A
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =10A, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C <sup>*4</sup>	-	-	1.4	V

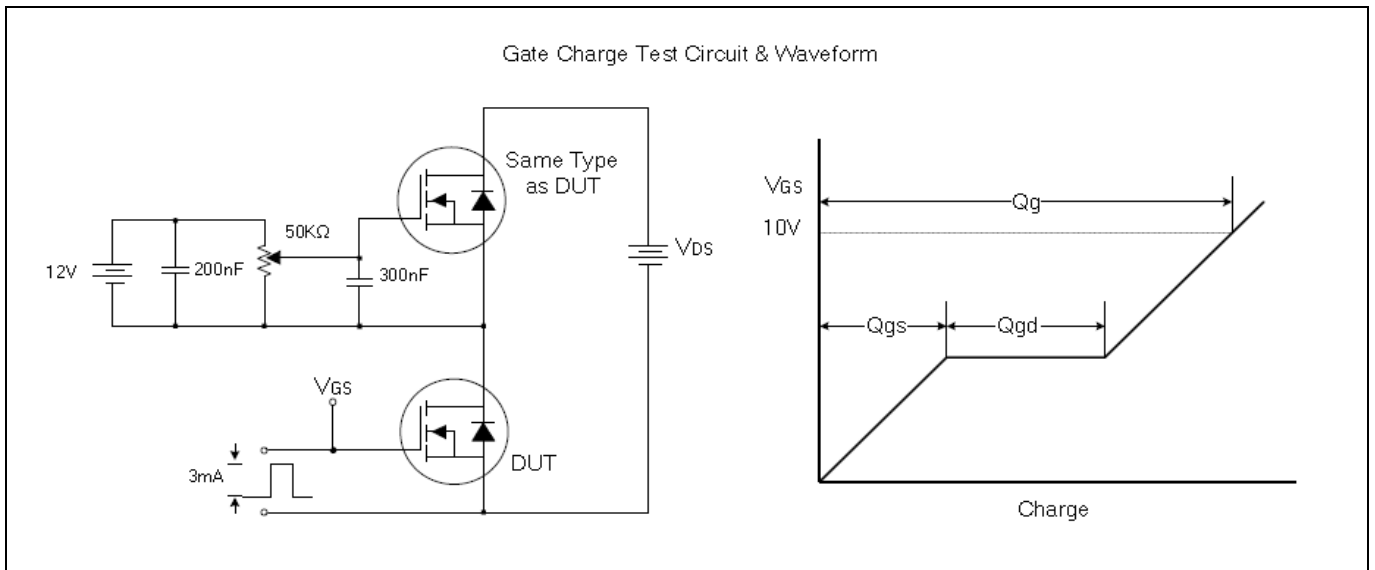
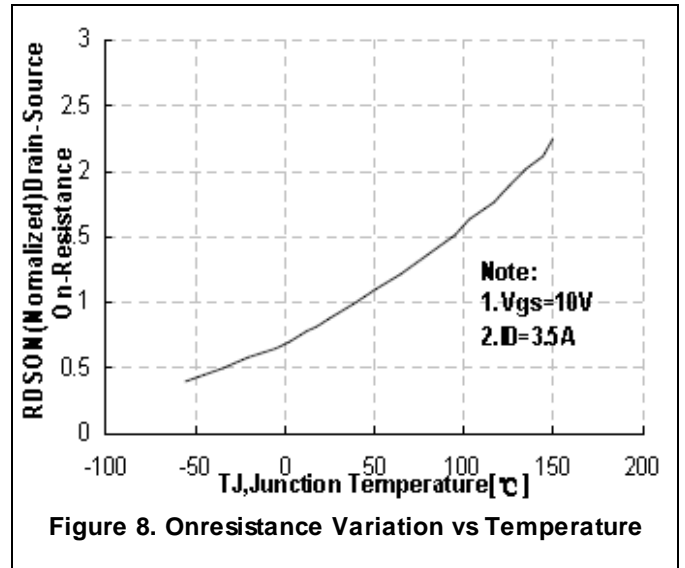
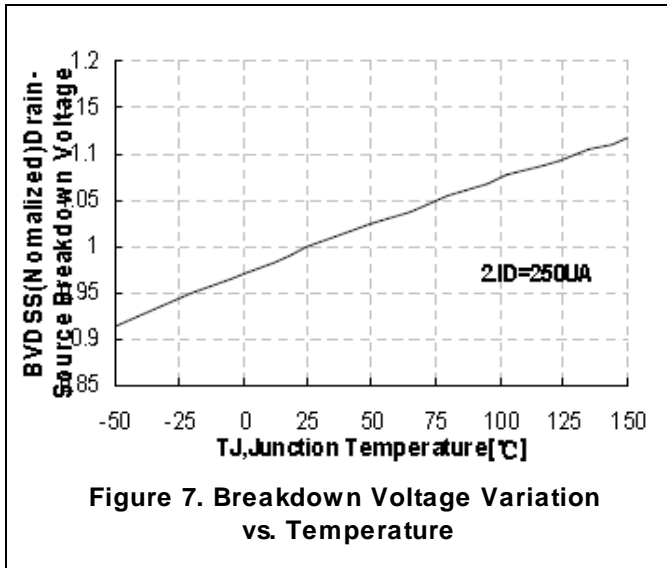
\*4: Pulse Test: Pulse Width≤300us, Duty Cycle≤2%

\*5: C<sub>oss</sub> eff. Is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>

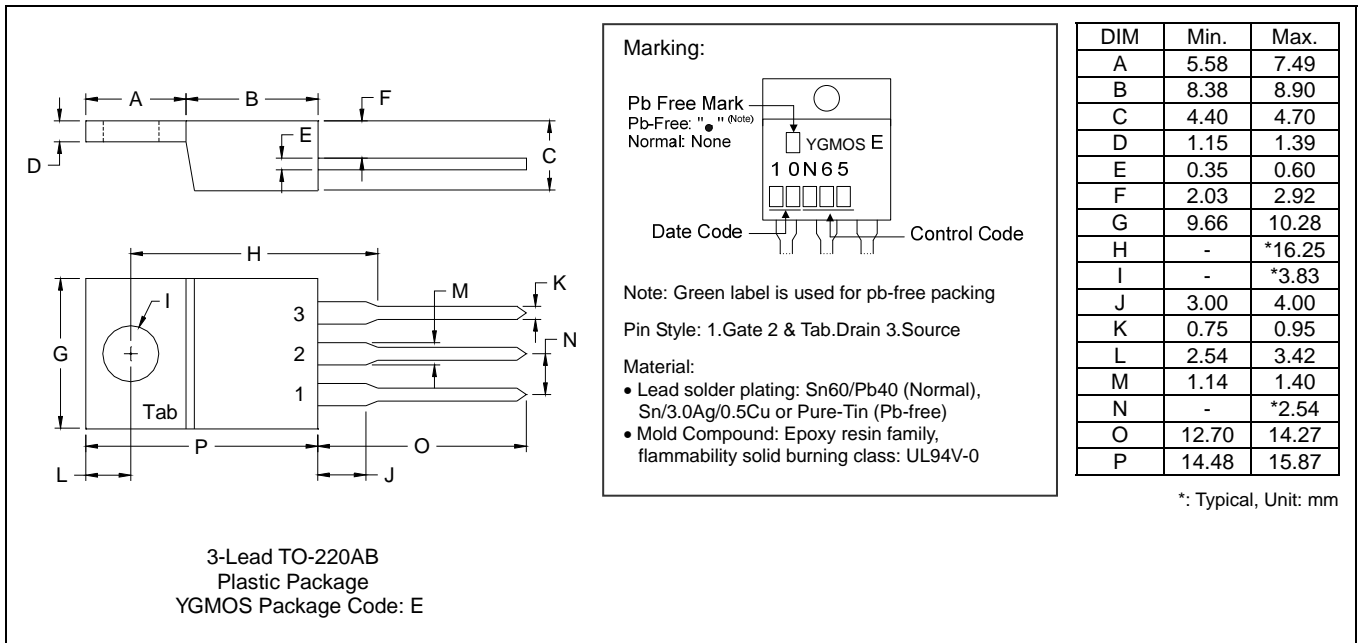
## Characteristics Curve



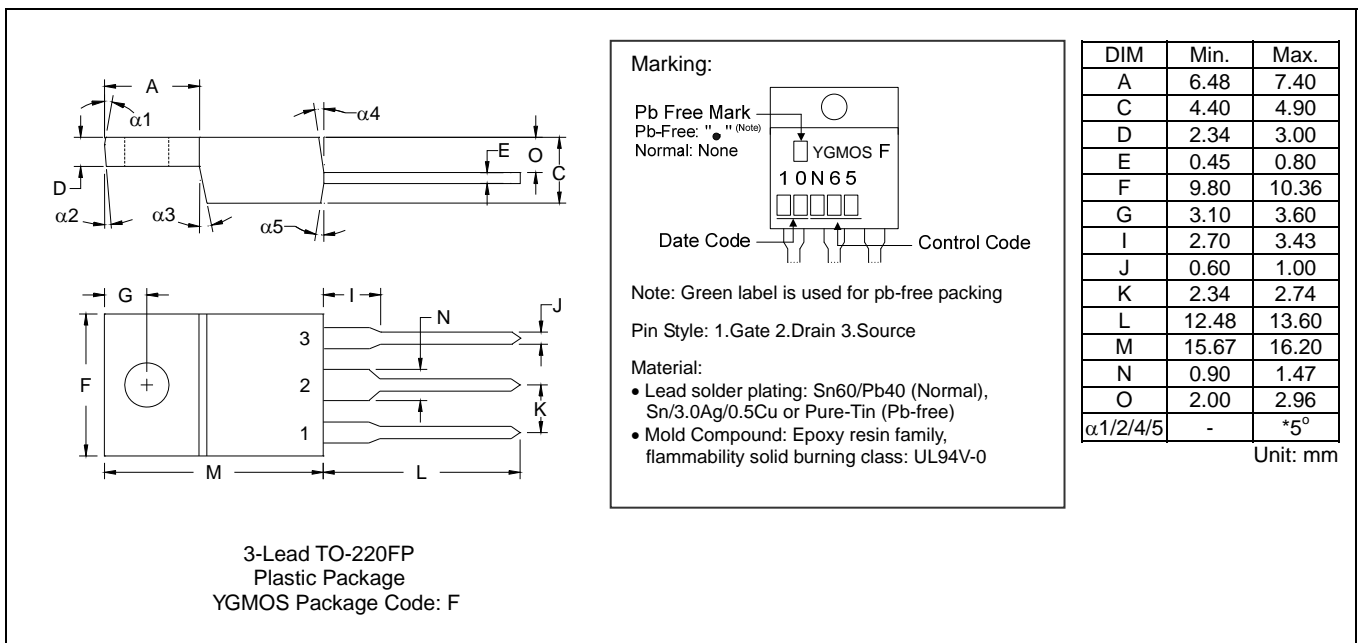
## Characteristics Curve



## TO-220AB Dimension



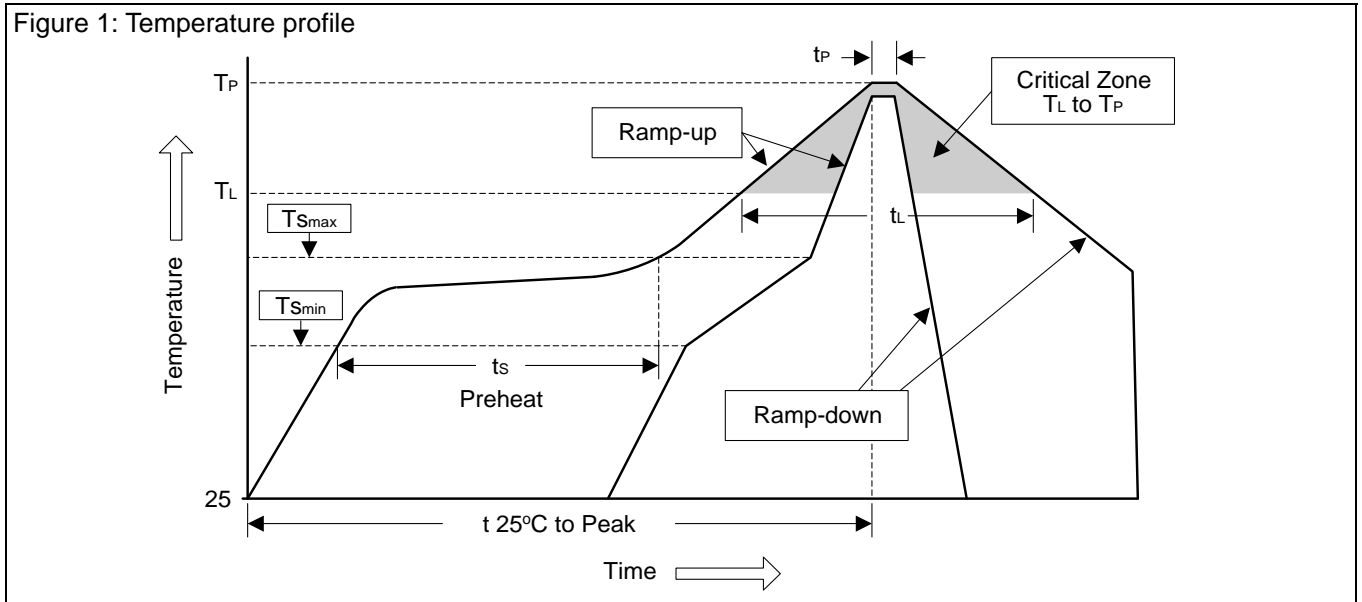
## TO-220FP Dimension



## Soldering Methods for YGMOS's Products

1. Storage environment: Temperature=10°C~35°C Humidity=65%±15%
2. Reflow soldering of surface-mount devices

Figure 1: Temperature profile



Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate ( $T_L$ to $T_P$ )	<3°C/sec	<3°C/sec
Preheat		
- Temperature Min ( $T_{Smin}$ )	100°C	150°C
- Temperature Max ( $T_{Smax}$ )	150°C	200°C
- Time (min to max) ( $t_s$ )	60~120 sec	60~180 sec
$T_{Smax}$ to $T_L$		
- Ramp-up Rate	<3°C/sec	<3°C/sec
Time maintained above:		
- Temperature ( $T_L$ )	183°C	217°C
- Time ( $t_L$ )	60~150 sec	60~150 sec
Peak Temperature ( $T_P$ )	240°C +0/-5°C	260°C +0/-5°C
Time within 5°C of actual Peak Temperature ( $t_p$ )	10~30 sec	20~40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25°C to Peak Temperature	<6 minutes	<8 minutes

3. Flow (wave) soldering (solder dipping)

Products	Peak temperature	Dipping time
Pb devices.	245°C ±5°C	5sec ±1sec
Pb-Free devices.	260°C +0/-5°C	5sec ±1sec